

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)**IEEE Xplore**
RELEASE 1.7Welcome
United States Patent and Trademark Office[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)[Quick Links](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

Print Format

Your search matched **8** of **1034809** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or enter a new one in the text box.

☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard**1 RSFQ circular shift registers***Mancini, C.A.; Vukovic, N.; Herr, A.M.; Gaj, K.; Bocko, M.F.; Feldman, M.J.;*
Applied Superconductivity, IEEE Transactions on , Volume: 7 , Issue: 2 , June

Pages:2832 - 2835

[\[Abstract\]](#) [\[PDF Full-Text \(492 KB\)\]](#) **IEEE JNL****2 Timing jitter and bit errors in a 64-bit circular shift register***Herr, A.M.; Feldman, M.J.; Bocko, M.F.;*
Applied Superconductivity, IEEE Transactions on , Volume: 9 , Issue: 2 , June

Pages:3721 - 3724

[\[Abstract\]](#) [\[PDF Full-Text \(404 KB\)\]](#) **IEEE JNL****3 High-speed operation of a 64-bit circular shift register***Herr, A.M.; Mancini, C.A.; Vukovic, N.; Bocko, M.F.; Feldman, M.J.;*
Applied Superconductivity, IEEE Transactions on , Volume: 8 , Issue: 3 , Sept 1998

Pages:120 - 124

[\[Abstract\]](#) [\[PDF Full-Text \(104 KB\)\]](#) **IEEE JNL****4 Implementation and application of first-in first-out buffers***Herr, Q.P.; Bunyk, P.;*
Applied Superconductivity, IEEE Transactions on , Volume: 13 , Issue: 2 , Jun 2003

Pages:563 - 566

[\[Abstract\]](#) [\[PDF Full-Text \(276 KB\)\]](#) IEEE JNL

5 Negative-inductance SQUID as the basic element of reversible Josephson-junction circuits

Semenov, V.K.; Danilov, G.V.; Averin, D.V.;

Applied Superconductivity, IEEE Transactions on , Volume: 13 , Issue: 2 , Jun 2003

Pages:938 - 943

[\[Abstract\]](#) [\[PDF Full-Text \(999 KB\)\]](#) IEEE JNL

6 A CMOS quadrature modulator for wireless communication IC

Lin, P.F.; Lou, J.H.; Kuo, J.B.;

Circuits and Systems I: Fundamental Theory and Applications, IEEE Transactions on [see also Circuits and Systems I: Regular Papers, IEEE Transactions on] , Volume: 44 , Issue: 6 , June 1997

Pages:559 - 561

[\[Abstract\]](#) [\[PDF Full-Text \(84 KB\)\]](#) IEEE JNL

7 New design of single-bit all-digital RSFQ autocorrelator

Rylyakov, A.V.;

Applied Superconductivity, IEEE Transactions on , Volume: 7 , Issue: 2 , June

Pages:2709 - 2712

[\[Abstract\]](#) [\[PDF Full-Text \(496 KB\)\]](#) IEEE JNL

8 Low power parallel spread-spectrum correlator

Garrett, D.; Stan, M.;

Circuits, Devices and Systems, IEE Proceedings [see also IEE Proceedings G-Circuits, Devices and Systems] , Volume: 146 , Issue: 4 , Aug. 1999

Pages:191 - 196

[\[Abstract\]](#) [\[PDF Full-Text \(508 KB\)\]](#) IEEE JNL

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE


[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)
IEEE Xplore®
 RELEASE 1.7

 Welcome
 United States Patent and Trademark Office


» Se

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

Print Format

Your search matched **5** of **1034809** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or enter a new one in the text box.

☐ Check to search within this result set
Results Key:**JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard**1 Single clock partial scan***Kwang-Ting Cheng;*Design & Test of Computers, IEEE , Volume: 12 , Issue: 2 , Summer 1995
Pages:24 - 31
[\[Abstract\]](#) [\[PDF Full-Text \(568 KB\)\]](#) **IEEE JNL**
2 An analysis of power reduction techniques in scan testing*Saxena, J.; Butler, K.M.; Whetsel, L.;*Test Conference, 2001. Proceedings. International , 30 Oct.-1 Nov. 2001
Pages:670 - 677
[\[Abstract\]](#) [\[PDF Full-Text \(630 KB\)\]](#) **IEEE CNF**
3 Advanced synchronous scan test methodology for multi clock domain ASICs*Schmid, J.; Knablein, J.;*VLSI Test Symposium, 1999. Proceedings. 17th IEEE , 25-29 April 1999
Pages:106 - 113
[\[Abstract\]](#) [\[PDF Full-Text \(248 KB\)\]](#) **IEEE CNF**
4 A simplified method for testing the IBM pipeline partial-scan microprocessor*Xinghao Chen; Snethen, T.; Swenton, J.; Walther, R.;*Test Symposium, 1999. (ATS '99) Proceedings. Eighth Asian , 16-18 Nov. 1999
Pages:321 - 326
[\[Abstract\]](#) [\[PDF Full-Text \(168 KB\)\]](#) **IEEE CNF**

5 Partial scan testing with single clock control*Agrawal, V.D.; Chakraborty, T.J.;*VLSI Test Symposium, 1993. Digest of Papers., Eleventh Annual 1993 IEEE ,
April 1993

Pages:313 - 315

[\[Abstract\]](#)[\[PDF Full-Text \(224 KB\)\]](#)**IEEE CNF**

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) |
[New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online](#)
[Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved